100V, 90A, 7.4mΩ N-channel Power SGT MOSFET

JMSH1008PGQ

Features

- Ultra-low ON-resistance, RDS(ON)
- Low Gate Charge
- 100% UIS Tested
- 100% ΔVds Tested
- Halogen-free; RoHS-compliant
- AEC-Q101 Qualified

Product Summary

Parameters	Value	Unit
V_{DSS}	100	V
$V_{GS(th)_Typ}$	3.1	V
I _D (@V _{GS} =10V)	90	Α
$R_{DS(ON)_Typ}(@V_{GS}=10V$	7.4	mΩ

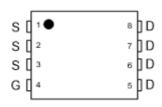


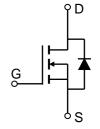
Applications

- Load Switch
- PWM Application
- General Automtoive Application









PDFN5X6-8L

Pin Assignment

Schematic Diagram

Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMSH1008PGQ-13	SH1008PQ	1	Tape&Reel	PDFN5x6-8L	5000	50000

Absolute Maximum Ratings (@ T_C = 25°C unless otherwise specified)

Symbol	Parameter		Value	Unit
V_{DS}	Drain-to-Source Voltage		100	V
V_{GS}	Gate-to-Source Voltage		±20	V
L Continuous Busin	Continuous Drain Current	$T_C = 25^{\circ}C$	90	^
I _D	Continuous Drain Current	$T_C = 100$ °C	64	A
I _{DM}	Pulsed Drain Current (1)		Refer to Fig.4	Α
E _{AS}	Single Pulsed Avalanche Energy (2)		265	mJ
P _D		$T_C = 25^{\circ}C$	150	W
		$T_C = 100$ °C	75] vv
T_{J}, T_{STG}	Junction & Storage Temperature Range		-55 to 175	°C

Thermal Characteristics

Symbol	Parameter	Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	44	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.0	C/VV



Electrical Characteristics (T_J = 25°C unless otherwise specified)

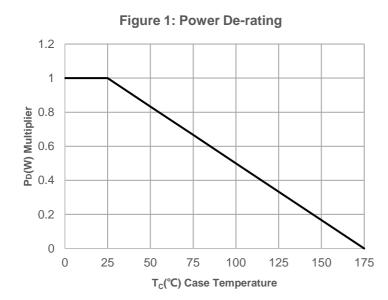
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Cha	racteristics					
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 80V, V_{GS} = 0V$	-	-	1.0	μА
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
On Cha	racteristics	•				
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.1	3.1	4.0	V
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 10V, I_D = 20A$	-	7.4	9.6	mΩ
Dynami	c Characteristics					
R_{g}	Gate Resistance	f = 1MHz	-	1.1	-	Ω
C _{iss}	Input Capacitance		1709	2393	3230	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 50V,$ f = 1MHz	305	426	576	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/2	16	22	29	pF
Qg	Total Gate Charge		28	39	53	nC
Q_{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 50V, I_{D} = 20A$	-	13	17	nC
Q_{gd}	Gate Drain("Miller") Charge	V DS = 30 V, ID = 20/1	-	10	13	nC
0 '(-1 '						
	ng Characteristics Turn-On DelayTime	I		44		
t _{d(on)}	, , , , , , , , , , , , , , , , , , ,	-	-	14		ns
t _r	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 50V$	-	22	-	ns
t _{d(off)}	Turn-Off DelayTime	$I_D = 20A, R_{GEN} = 3\Omega$	-	27	-	ns
t _f	Turn-Off Fall Time		-	10	-	ns
	iode Characteristics	<u> </u>				I .
I _S	Maximum Continuous Body Diode Forward		-	-	90	Α
I _{SM}	Maximum Pulsed Body Diode Forward Curre		-	-	360	Α
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V$, $I_S = 20A$	-		1.2	V
trr	Body Diode Reverse Recovery Time	I _F = 15A, di/dt = 100A/us	42	59	79	ns
Qrr	Body Diode Reverse Recovery Charge	1- 10/1, and - 100/1/43	-	126	-	nC

Notes:

- 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
- $2.\;E_{AS}\;condition:\;Starting\;T_J=25C,\;V_{DD}=50V,\;V_G=10V,\;R_G=25ohm,\;L=3mH,\;I_{AS}=13.3A,\;V_{DD}=0V\;during\;time\;in\;avalanche.$
- 3. $R_{\theta JA}$ is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB.
- 4. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 0.5%.



Typical Performance Characteristics



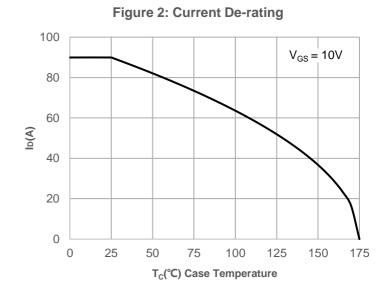
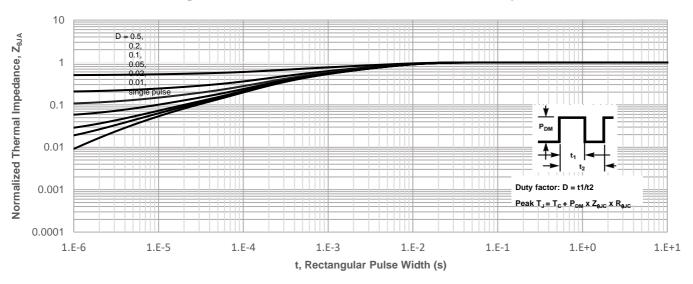
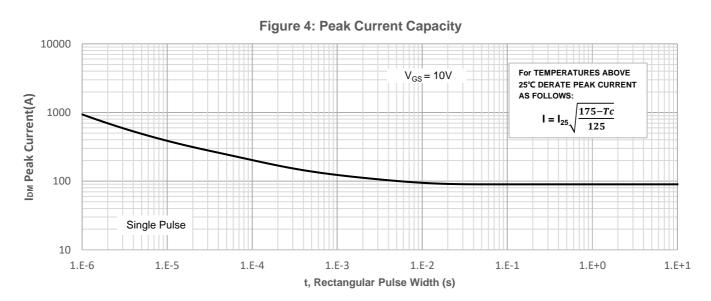


Figure 3: Normalized Maximum Transient Thermal Impedance







Typical Performance Characteristics

Figure 5: Output Characteristics

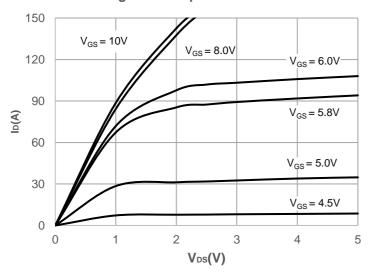


Figure 6: Typical Transfer Characteristics

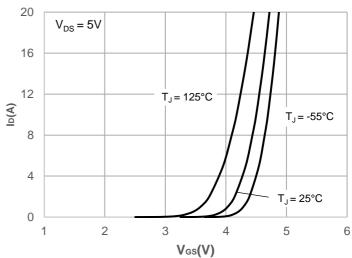


Figure 7: On-resistance vs. Drain Current

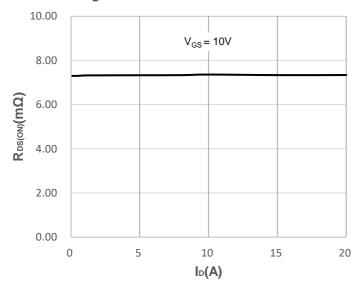


Figure 8: Body Diode Characteristics

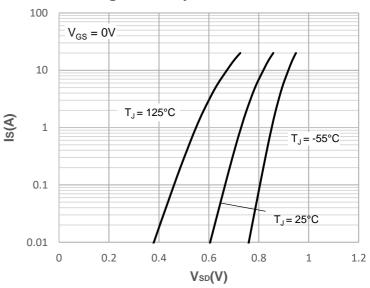


Figure 9: Gate Charge Characteristics

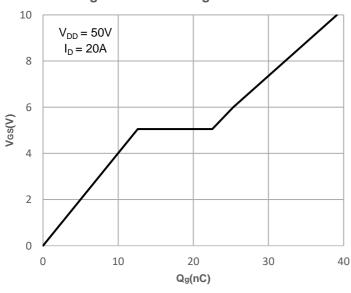
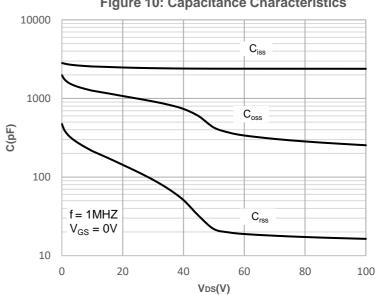


Figure 10: Capacitance Characteristics





Typical Performance Characteristics

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

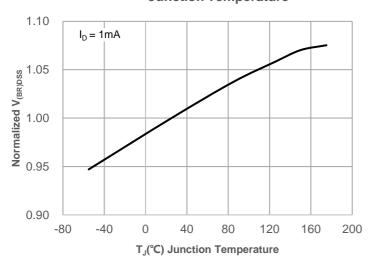


Figure 13: Normalized Threshold Voltage vs. Junction Temperature

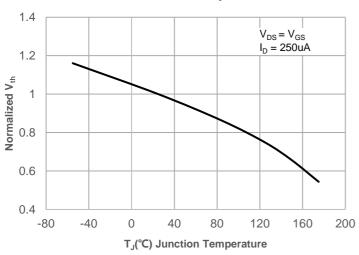


Figure 15: Maximum Safe Operating Area

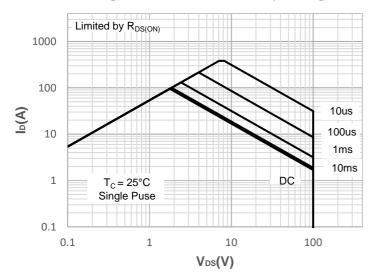
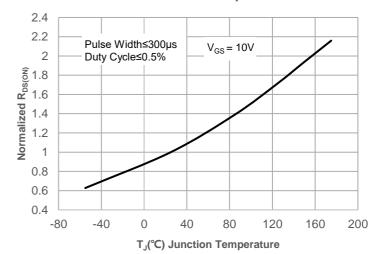
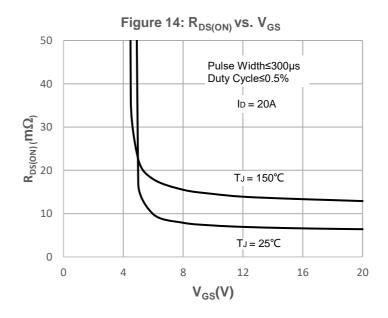


Figure 12: Normalized on Resistance vs. Junction Temperature







Test Circuit

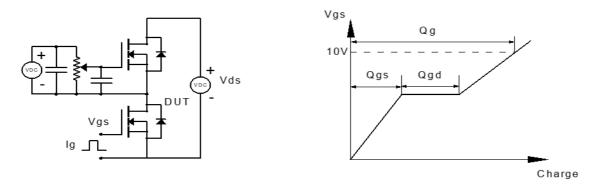


Figure 1: Gate Charge Test Circuit & Waveform

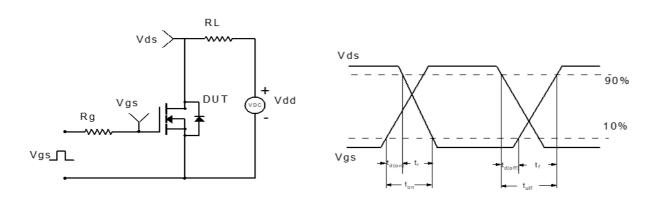


Figure 2: Resistive Switching Test Circuit & Waveform

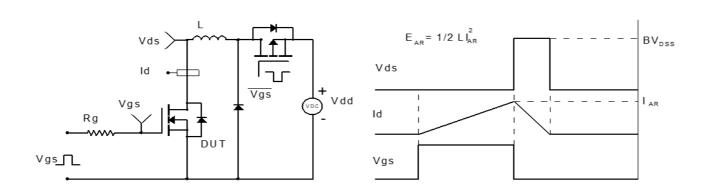


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

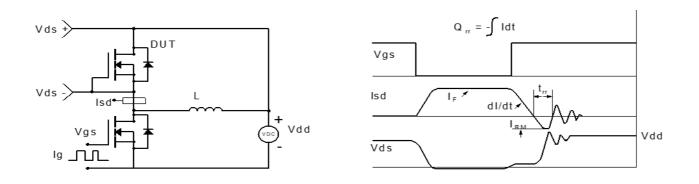
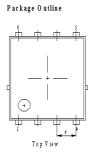


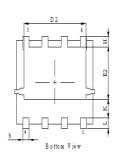
Figure 4: Diode Recovery Test Circuit & Waveform

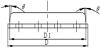


Package Mechanical Data(PDFN5X6-8L)





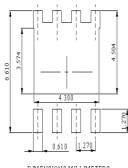




ES:
Dimension and tolerance per ASMEY14.5M, 1994.
All dimensions in millimeter (angle in degree).
Dimensions D1 and E1 do not include mold flash protrusions or gate burrs

	MILLIMETER			
DIM.	MIN.	NOM.	MAX.	
A	0. 9	1	1. 15	
b	0.31	0.41	0.51	
С	0. 24	0. 32	0. 4	
D	5	5. 2	5. 4	
D1	4. 95	5. 05	5. 15	
D2	4	4. 1	4. 2	
E	6, 05	6. 15	6. 25	
E1	5. 5	5. 6	5. 7	
E2	3. 42	3, 53	3, 63	
е	1. 27BSC			
Н	0.6	0.7	0.8	
L	0. 5	0. 7	0.8	
K	1. 23 REF			
0			10	

Recommended Soldering Footprint



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